

Search Notes

Application/Control No.

10/679,856

Examiner

Pablo N. Tran

Applicant(s)/Patent under
Reexamination

BODNAR ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
458	556.1	05/08/06	P
	556.2		
	550.1		
	40.3		
	426.1		
	578.1		
	66.1		
	557		
	566		
	575.9		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner